

# CBCS SCHEME

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20ELD14

## First Semester M.Tech. Degree Examination, Jan./Feb. 2023 Digital Circuits and Logic Design

Time: 3 hrs.

Max. Marks: 100

*Note: Answer any FIVE full questions, choosing ONE full question from each module.*

### Module-1

- 1 a. Define threshold function and unite function. (10 Marks)  
 b. Given the switching function:  
 $f(x_1, x_2, x_3, x_4) = \sum(2, 3, 6, 7, 10, 12, 14, 15)$ . Find a minimal threshold logic realization. (10 Marks)

**OR**

- 2 a. Find whether function  $f(x_1, x_2, x_3, x_4) = \sum(0, 8, 9, 10, 11, 12, 13, 14)$  is unite. If it is find its minimal true and maximal false vertices. Write the linear equations. (10 Marks)  
 b. Consider the switching function 'f'  $f(x_1, x_2, x_3, x_4) = \sum(3, 5, 7, 10, 12, 14, 15)$ . Find a minimal threshold logic realization. (10 Marks)

### Module-2

- 3 a. Explain with an example a fault detection by path sensitizing method. (10 Marks)  
 b. Use the map method to find a minimal set of tests for multiple faults for the 2-level AND-OR realization of the function  $f(w, x, y, z) = (w\bar{z} + x\bar{y} + \bar{w}x + w\bar{x}y)$ . (10 Marks)

**OR**

- 4 a. Find all the static hazards in the circuit shown in Fig.Q.4(a). How will you eliminate those static hazards? (10 Marks)

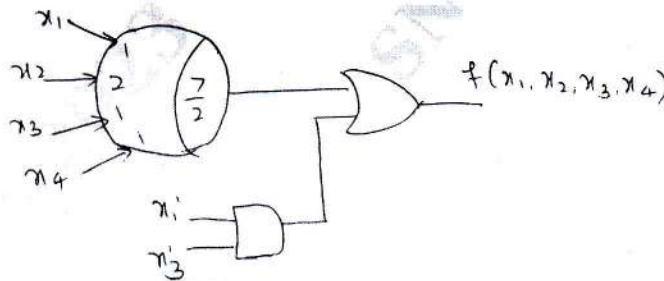


Fig.Q.4(a)

(10 Marks)

- b. Use the map method to find a minimal set of tests for multiple faults for the 2-level OR-NAND realization of the function  $f = (A + B)(B + C + \bar{D})(\bar{A} + \bar{B} + \bar{C} + \bar{D})$ .

Important Note : 1. On completing your answers, compulsorily draw diagonal cross lines on the remaining blank pages.  
 2. Any revealing of identification, appeal to evaluator and /or equations written eg, 42-8 = 50, will be treated as malpractice.

**Module-3**

- 5 a. Find the equivalence partition for machine shown in Table Q.5(a), draw the reduced machine and show a standard form of a corresponding reduced machine.

Table Q.5(a)

| PS | NS, Z |       |
|----|-------|-------|
|    | x = 0 | x = 1 |
| A  | B, 1  | H, 1  |
| B  | F, 1  | D, 1  |
| C  | D, 0  | E, 1  |
| D  | C, 0  | F, 1  |
| E  | D, 1  | C, 1  |
| F  | C, 1  | C, 1  |
| G  | C, 1  | D, 1  |
| H  | C, 0  | A, 1  |

(10 Marks)

- b. Find the tests to detect the faults at  $x_3$ , s-a-0 and s-a-1 for the circuit shown in Fig.Q.5(b).

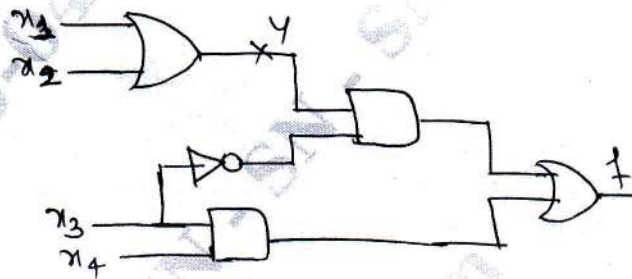


Fig.Q.5(b)

(10 Marks)

**OR**

- 6 a. Draw the merger graph and its minimal form for the machine in Table Q.6(a). Also write its merger table.

Table Q.6(a)

| PS | NS, Z          |                |                |                |
|----|----------------|----------------|----------------|----------------|
|    | I <sub>1</sub> | I <sub>2</sub> | I <sub>3</sub> | I <sub>4</sub> |
| A  | -              | C, 1           | E, 1           | B, 1           |
| B  | E, 0           | -              | -              | -              |
| C  | F, 0           | F, 1           | -              | -              |
| D  | -              | -              | B, 1           | -              |
| E  | -              | F, 0           | A, 0           | D, 1           |
| F  | C, 0           | -              | B, 0           | C, 1           |

(10 Marks)

- b. Explain the adaptive 4-level tree and 3-level tree by considering  $T_2$  and  $T_6$  as initial test for the fault table shown in Table Q.6(b).

Table Q.6(b)

| Tests          | f <sub>0</sub> | f <sub>1</sub> | f <sub>2</sub> | f <sub>3</sub> | f <sub>4</sub> | f <sub>5</sub> | f <sub>6</sub> | o/p of fault free circuit |
|----------------|----------------|----------------|----------------|----------------|----------------|----------------|----------------|---------------------------|
| T <sub>1</sub> |                |                |                |                |                | 1              | 1              | 0                         |
| T <sub>2</sub> |                | 1              |                | 1              |                | 1              |                | 1                         |
| T <sub>3</sub> |                |                |                |                | 1              | 1              |                | 0                         |
| T <sub>4</sub> |                |                | 1              | 1              |                |                |                | 1                         |
| T <sub>5</sub> |                | 1              |                |                |                |                | 1              | 0                         |
| T <sub>6</sub> |                | 1              |                | 1              |                |                | 1              | 1                         |

(10 Marks)

**Module-4**

- 7 a. For the machine in Table Q.7(a), determine the  $\pi$ -lattice and basic partitions. Also show the derivation of the basic partitions.

Table Q.7(a)

| PS | NS    |       |
|----|-------|-------|
|    | x = 0 | x = 1 |
| A  | E     | B     |
| B  | E     | A     |
| C  | D     | A     |
| D  | C     | F     |
| E  | F     | C     |
| F  | E     | C     |

- b. Explain: i) Input-Consistent ii) Output-Consistent iii) Closed partitions.

(10 Marks)

(10 Marks)

**OR**

- 8 a. For the machine given in Table Q.8(a), Find:

i) Closed partitions

ii) Given the functional relationship based on the

$$\tau_1 = \{\overline{A, B, C, D}; \overline{E, F, G, H}\}, \quad \tau_2 = \lambda_0 = \{\overline{A, C, E, G}; \overline{B, D, F, H}\}.$$

iii) Write down the schematic diagram and  $\pi$ -lattice for machine given in Table Q.8(a).

Table Q.8(a)

| PS | NS    |       | Z |
|----|-------|-------|---|
|    | x = 0 | x = 1 |   |
| A  | G     | D     | 1 |
| B  | H     | C     | 0 |
| C  | F     | G     | 1 |
| D  | E     | G     | 0 |
| E  | C     | B     | 1 |
| F  | C     | A     | 0 |
| G  | A     | E     | 1 |
| H  | B     | F     | 0 |

- b. For the machine shown in Table Q.8(b), find:

i)  $\pi$  - lattice and schematic diagram

ii) Non-trivial closed partitions

iii) Parallel decompositions.

Table Q.8(b)

| PS | NS    |       | Z |
|----|-------|-------|---|
|    | x = 0 | x = 1 |   |
| A  | D     | G     | 0 |
| B  | C     | E     | 0 |
| C  | H     | F     | 0 |
| D  | F     | F     | 0 |
| E  | B     | B     | 0 |
| F  | G     | D     | 0 |
| G  | A     | B     | 0 |
| H  | E     | C     | 1 |

(10 Marks)

(10 Marks)

**Module-5**

- 9 a. Explain the Homing Experiment. Write down the Homing tree for the machine M shown in Table Q.9(a).

Table Q.9(a)

| PS | NS, Z |       |
|----|-------|-------|
|    | x = 0 | x = 1 |
| A  | B, 0  | D, 0  |
| B  | A, 0  | B, 0  |
| C  | D, 1  | A, 0  |
| D  | D, 1  | C, 0  |

(10 Marks)

- b. i) What is the main feature of the second algorithm for the design of fault detection experiments?  
 ii) Write down the general procedure of the second algorithm.

(10 Marks)

**OR**

- 10 a. Explain and write down the successor tree for the machine shown in Table Q.10(a).

Table Q.10(a)

| PS | NS, Z |       |
|----|-------|-------|
|    | x = 0 | x = 1 |
| A  | C, 0  | D, 1  |
| B  | C, 0  | A, 1  |
| C  | A, 1  | B, 0  |
| D  | B, 0  | C, 1  |

(10 Marks)

- b. Explain the adaptive distinguishing experiment by considering the machine shown in Table Q.10(b).

Table Q.10(b)

| PS | NS, Z |       |
|----|-------|-------|
|    | x = 0 | x = 1 |
| A  | C, 0  | A, 1  |
| B  | D, 0  | C, 1  |
| C  | B, 1  | D, 1  |
| D  | C, 1  | A, 0  |

(10 Marks)

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